

1st IBM Academy Conference on
Analog Design, Technology, Modeling and Tools

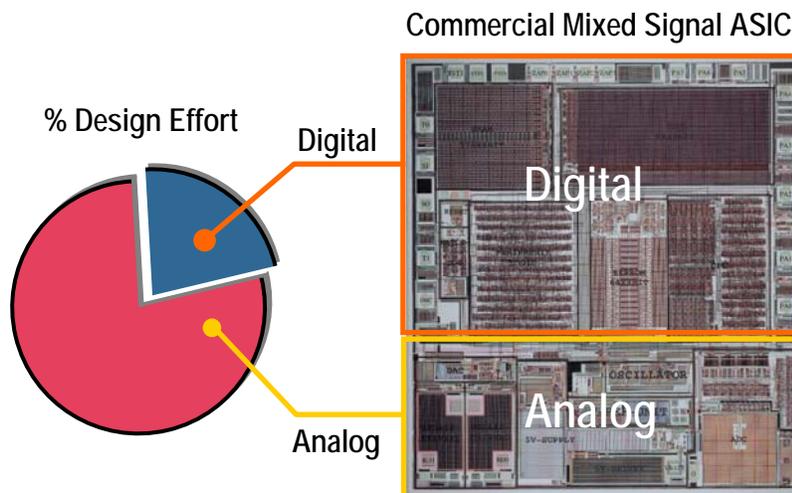
Design Automation for Analog: The Next Generation of Tool Challenges

Rob A. Rutenbar
Professor, Electrical & Computer Engineering
rutenbar@ece.cmu.edu

© R.A. Rutenbar 2006

CarnegieMellon

The Mixed-Signal Design Problem



© R.A. Rutenbar 2006 Slide 2

Why This Happens—Historical View



Analog Methodology

- CAD tools
- Abstraction
- Reuse & IP

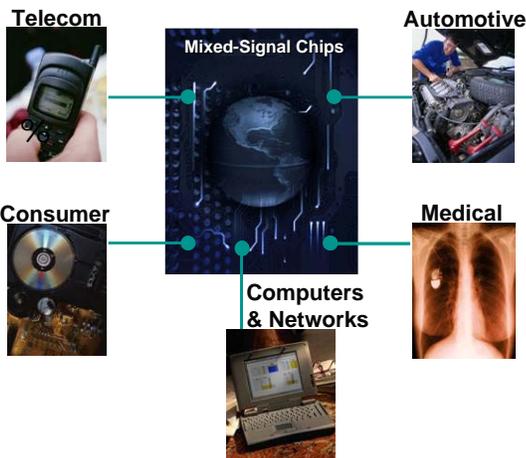


Digital Methodology

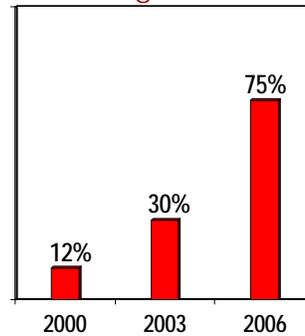
- CAD tools
- Abstraction
- Reuse & IP

© R.A. Rutenbar 2006 Slide 3

Why This Matters (I): Many “Mixed-Signal” ICs



% Digital Chips with Analog Content



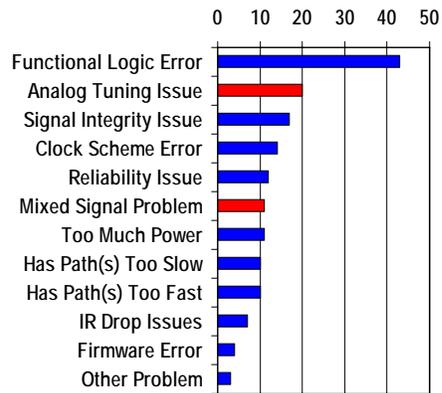
[Source: IBS 2003]

© R.A. Rutenbar 2006 Slide 4

Why This Matters (II): Analog Mistakes == \$\$\$

- How many ICs/ASICs work on first silicon? **Only 39%**
 - 61% of new ICs/ASICs require at least one re-spin.
 - Source: Aart de Geus, Chairman & CEO of Synopsys, 2003 Boston SNUG
- Many silicon failures are due to **analog / mixed-signal** design error
- This is a **very** expensive problem...

First Silicon Failures (%)



© R.A. Rutenbar 2006 Slide 5

The Challenges...

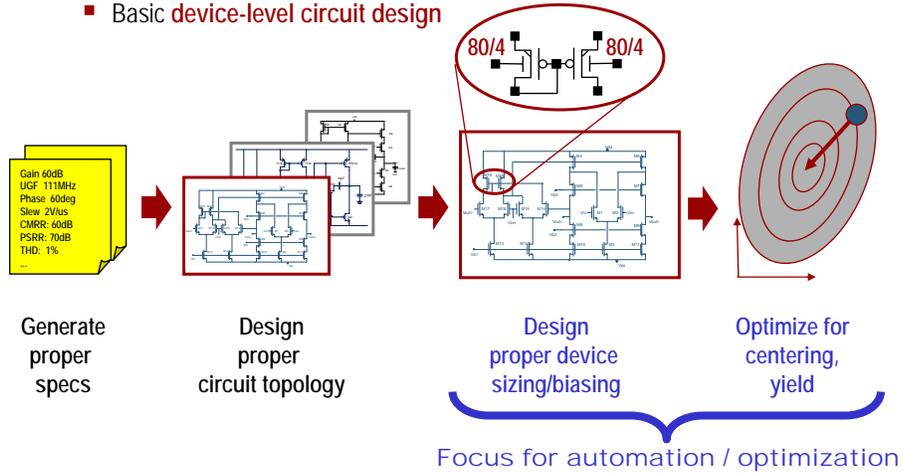
- **Constant** need for better tools
- Tools for productivity
- Tools for complexity
- Tools for technology (scaling)
- Tools for reuse / IP



Analog Circuit Design: Sizing/Centering Tools

■ No matter *how* you do it, you have to do these tasks

- Basic **device-level circuit design**

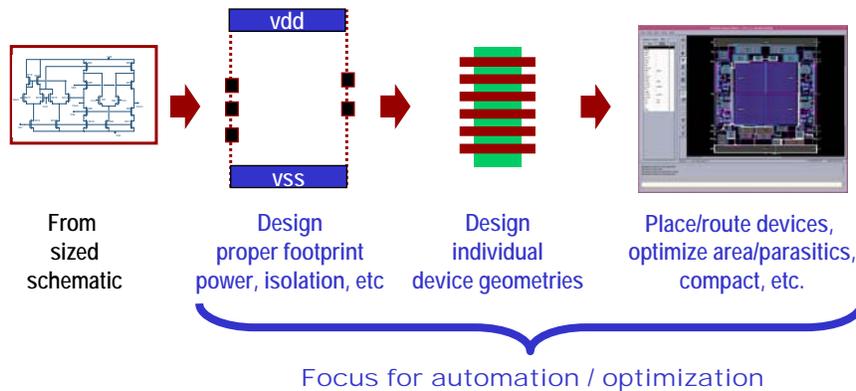


© R.A. Rutenbar 2006 Slide 9

Analog Circuit Design: Layout Tools

■ No matter *how* you do it, you have to do these tasks

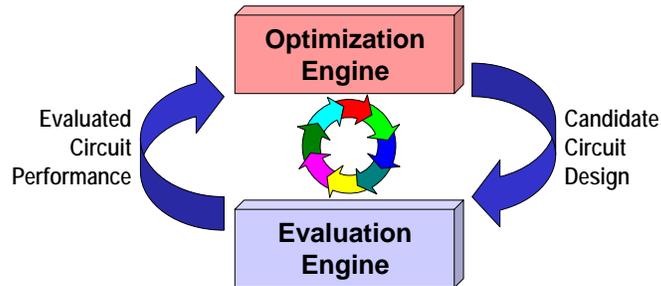
- Basic **device-level layout design**



© R.A. Rutenbar 2006 Slide 10

The Strategy: *Optimization-Based Design*

- All successful approaches have this overall structure



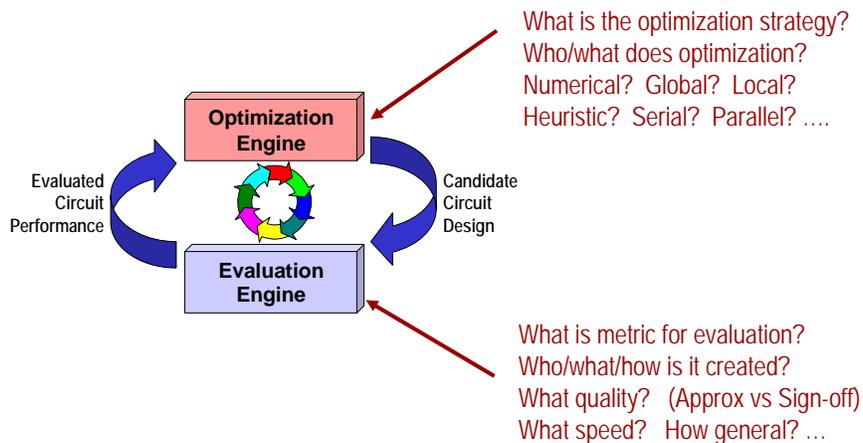
- Use some clever form of heuristic or numerical search

- **Optimization engine:** proposes candidate circuit solutions
- **Evaluation engine:** evaluates quality of each candidate
- **Cost-based search:** cost metric represents "goodness" of design

© R.A. Rutenbar 2006 Slide 11

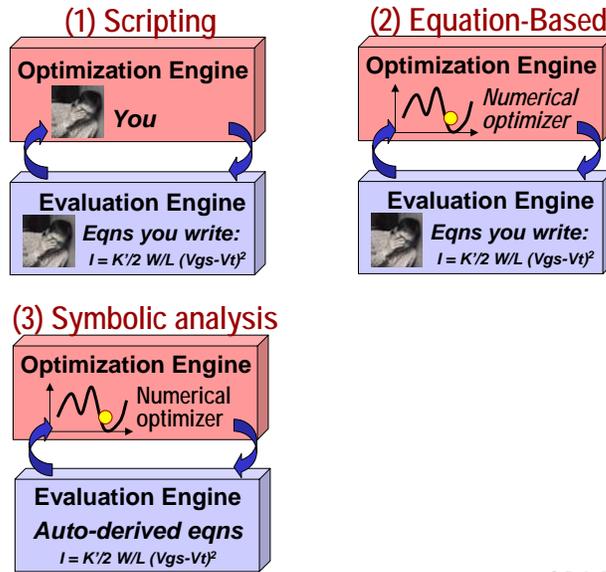
Sizing Optimization: Short Historical Tour

- Can use diagram to characterize major optimization-based ideas



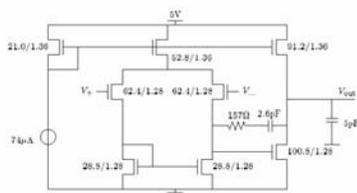
© R.A. Rutenbar 2006 Slide 12

The History: Four Major Approaches

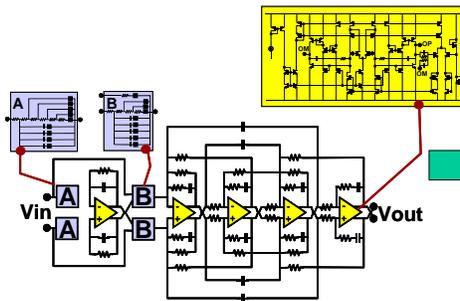


© R.A. Rutenbar 2006 Slide 13

Problems with Scripting/Equations/Symbolic



Tell me gain/bandwidth
 for this opamp, ~10 devices
 == *easy*



Tell me noise, THD,
 across all 6 operating settings
 of the configuration switches
 for this equalizer/filter frontend
 for a commercial ADSL receiver
 ~400 devices == *hard*

© R.A. Rutenbar 2006 Slide 14

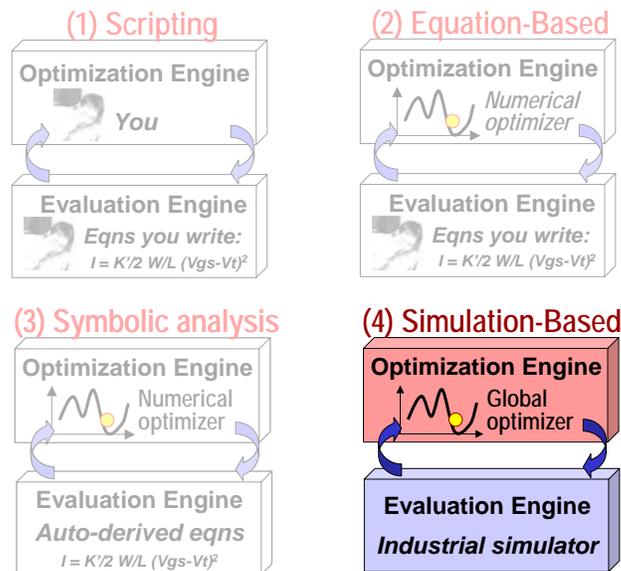
Aside: Commercial Scripting/ Eqn / Symbolic Efforts

- Marketplace has *not* been kind to these synthesis approaches



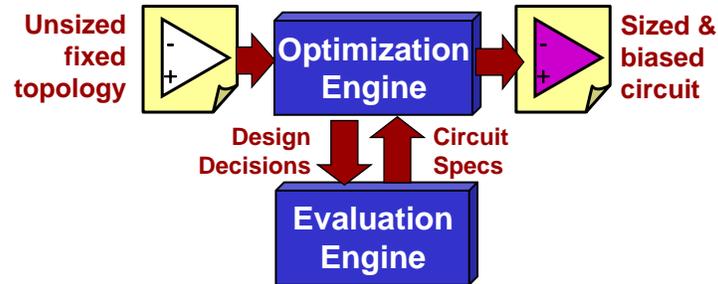
© R.A. Rutenbar 2006 Slide 15

Back to our Historical Tour: What's Left?



© R.A. Rutenbar 2006 Slide 16

Analog Sizing Synthesis: Basic Architecture



Why it works

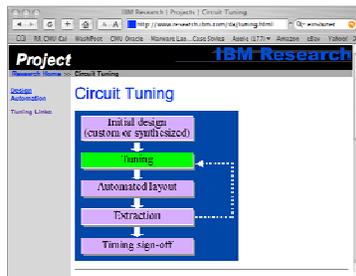
- Eval engine is the same one designer uses, trusts for manual verification
- Fast, cheap computers make it easy to use network parallelism for speed
- Smart optimizers can deal with even very difficult circuit problems

© R.A. Rutenbar 2006 Slide 17

Idea Should Not Be Unfamiliar to IBM

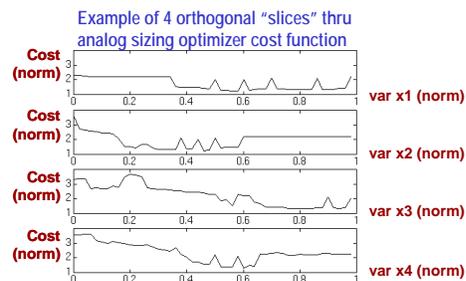
IBM tuner tools, eg, *EinsTuner*

- Large-scale optimizer
- Adjusts device sizing
- Simulation (circuit, timing) in loop
- Very successfully applied



What's different for analog case?

- *Smaller* problems (10s – 100s devices)
- Simulator *independent*; runs on *network*
- *Not* smooth, *not* differentiable
- *Cannot* use friendly gradient optimiz
- Starting circuit may *not* be functional

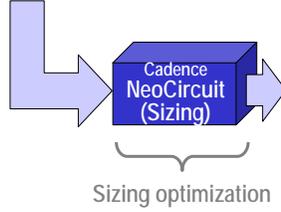
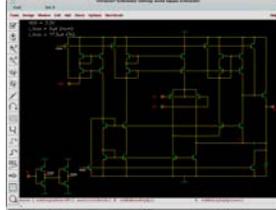


© R.A. Rutenbar 2006 Slide 18

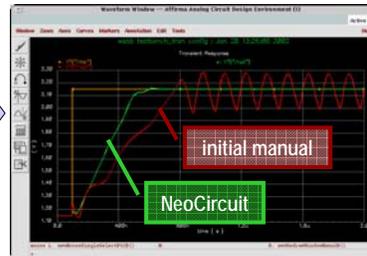
Industrial Applications

Infineon result [Hennig, Sommer, Charlack, DATE02]

CMOS Folded Cascode Amp



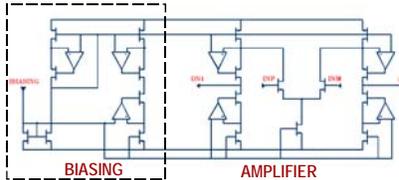
Performance	Specification	Result
Supply voltage	3.3 V	
Load	10 MΩ 10 pF	
DC Gain	> 90 dB	90.47 dB
Gain margin	> 3	3.152
Phase margin	> 60°	60.49°
Unity-gain frequency	> 2 MHz	2.972 MHz
PSRR	> 100 dB	120.9 dB
CMRR	> 110 dB	117.7 dB
Offset	< 1 mV	752.5 μV
Slew rate	> 1 V/μs, maximize!	2.331 V/μs
Settling time	< 500 ns	490.9 ns
Overshoot	< 50 mV	5.673 mV
Power	< 300 μW, minimize!	297.4 μW



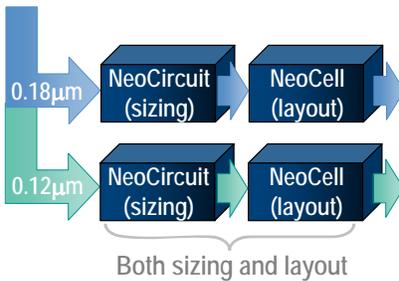
© R.A. Rutenbar 2006 Slide 19

Industrial Applications

STMicroelectronics result [Shah, Dugalleix, Lemery DATE02]



	GOALS at 0.18μm	RESULTS 0.18μm Corners	RESULTS 0.12μm Corners
DC Gain	> 70 dB	70 dB	70.3 dB
UGF	> 600 MHz	1.1 GHz	2.17 GHz
Phase Margin	> 45°	48°	49.2°
Settling Time	< 8 ns	7.4 ns	5.77 ns
Slew	> 400 V/μs	1900 V/μs	1620 V/μs
Power	< 10 mW	9.15 mW	1.1 mW

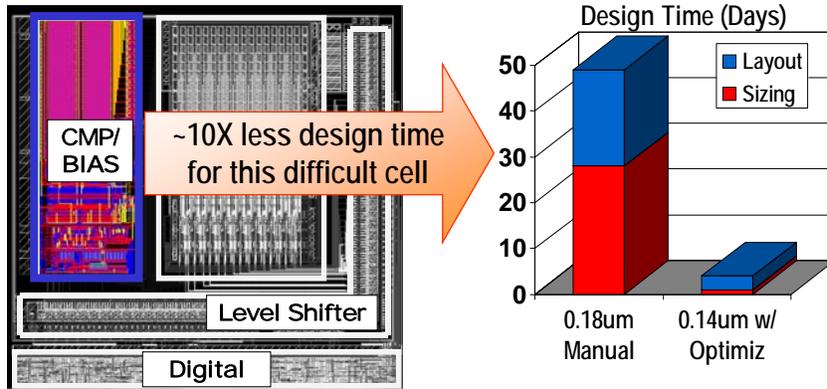


© R.A. Rutenbar 2006 Slide 20

Industrial Applications

■ Toshiba result

- Porting a data converter from 0.18 μm to 0.14 μm



© R.A. Rutenbar 2006 Slide 21

Mid-Point Summary

■ Analog synthesis / optimization tools

- Lots of progress over last decade
- Moving (finally) from research into production
- Moving (s l o w l y) from research into production

■ What's next...?

- *Lots..*

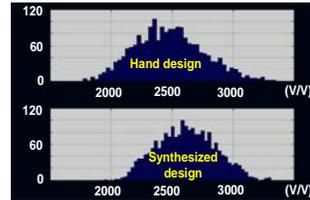
© R.A. Rutenbar 2006 Slide 22

What's Next?

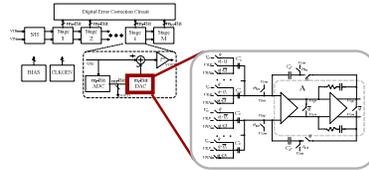
■ (1) Usability



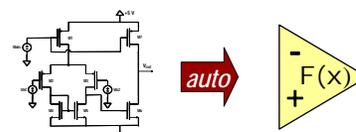
■ (2) Statistical variability



■ (3) Scalability: Circuits → Systems



■ (4) Systematic macromodeling



© R.A. Rutenbar 2006 Slide 23

(1) Usability: Near-Term Challenge

- Yes Virginia – the tools can be *challenging* to use...



© R.A. Rutenbar 2006 Slide 24

Usability Issues

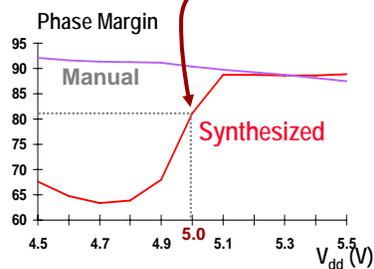
- Some *myths* about analog optimization tools
 - They're *impossible* to set up and use
 - They're *brainless* – hitting a mosquito with a bazooka
 - They're *slow*
- Some *truths*
 - They're *hard* to set set up and use (we're working on it...)
 - They can be used very *intelligently* (if you're willing to invest in setup)
 - They're not so slow when you set them up *correctly*

© R.A. Rutenbar 2006 Slide 25

Why So Hard To Use? Constraint Mgt

- Optimizers give you *exactly* what you ask for – not one thing more
- Analog designs exceptionally rich in critical – *implicit* – constraints

Example (in older tech) :
Please make
Phase Margin $\geq 77^\circ$
at $V_{dd} = 5.0V$



© R.A. Rutenbar 2006 Slide 26

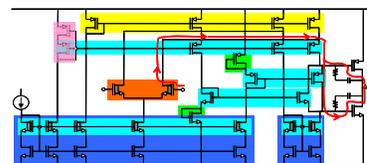
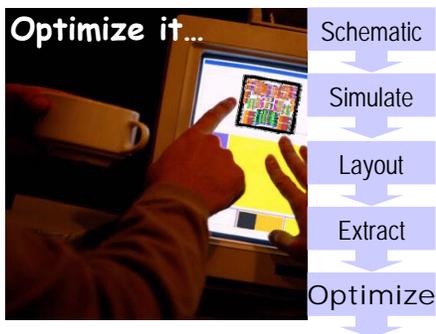
Robust Constraint Acquisition: *Big Problem*



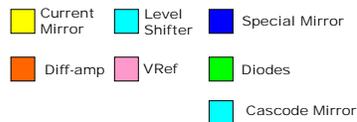
Robust Constraint Acquisition & Management

- Much of this is just good integration, GUI, database work

- Interesting research on scriptable electrical/geometric constraint recognition and enforcement

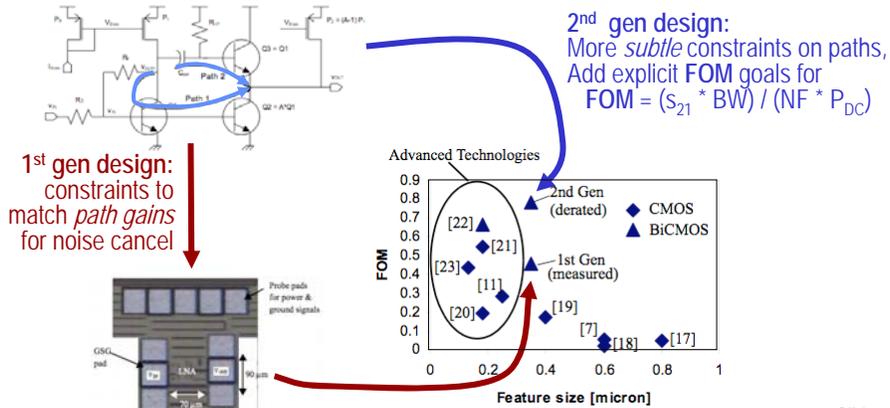


TI low noise amplifier in an ADSL receiver codec



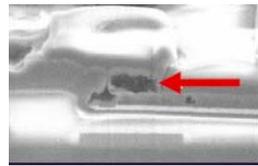
Final Point: Using Optimizers *Smart*

- Actually desirable to augment optimization setup with “smart” constraints – if you know them, put them in
 - Example: noise canceling wideband amp, after [Nauta JSSC04], from [Mukherjee et al, GLVLSI06], in 0.35um SiGe, done with Cadence optimizer



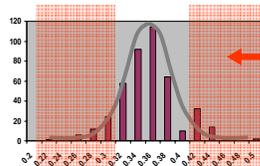
(2) Statistics: Long-Term Challenge for Yield Loss

- Process defects

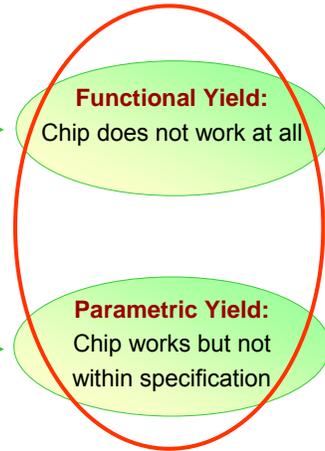


Failure due to void

- Environmental / process variations



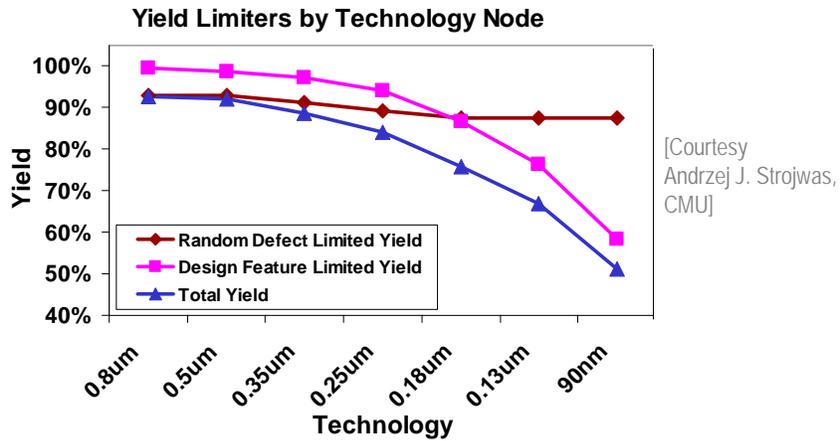
Out of spec



[Courtesy Andrzej J. Strojwas, CMU]

© R.A. Rutenbar 2006 Slide 30

What Effects Limit Yield, As Technology Scales?

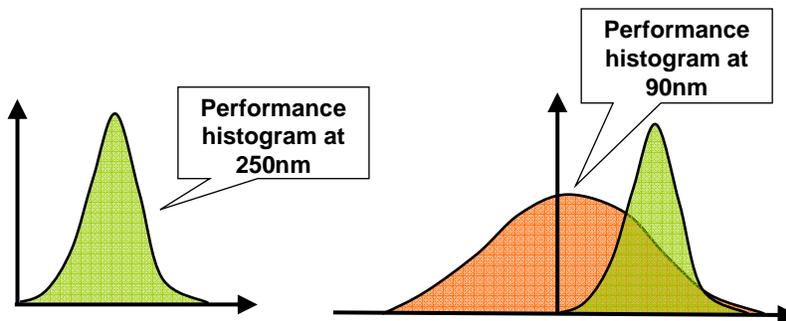


- Random defects are no longer the dominant yield loss mechanism
 - Yields are now limited by *design features*, *systematic* and *parametric* effects

© R.A. Rutenbar 2006 Slide 31

Analog Circuit Performance Variation *Increases*

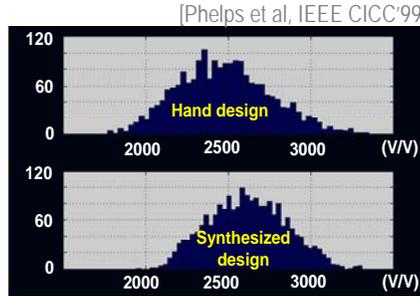
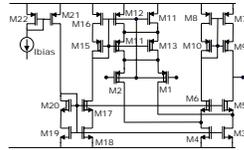
- Analog always more sensitive to physics of fab process
 - Analog exploits rather than abstracts away basic nonlinearities of devices
 - Devices optimized for digital switching are increasingly lousy for analog



© R.A. Rutenbar 2006 Slide 32

New Challenge: Statistically-Aware Optimization

- Good news: sim-based methods handle mfg corners easily
 - Sample result for TI circuit's low frequency gain; set up w/ *ad hoc* mfg constraints
 - 3σ process, +/-10% supply and temperature variations



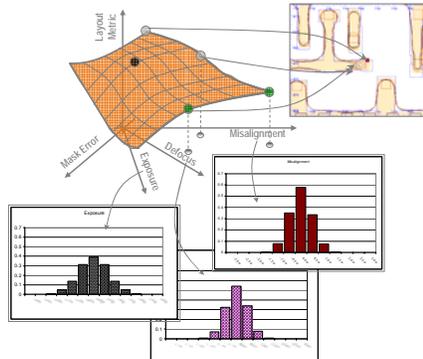
- Bad news: corners are no longer sufficient to ensure success
 - Too many corners, too much complexity, correlated behavior among statistics

© R.A. Rutenbar 2006 Slide 33

Broadly, Two Different Approaches

- Response surface methods (RSM)

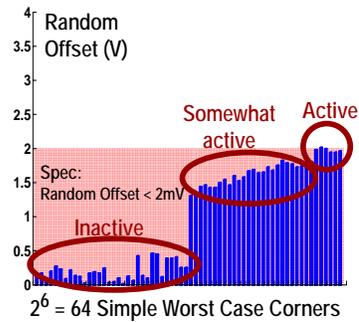
- Build a low-order model of how process disturbances affect design
- Optimize on this surface



[Litho/Layout RSM from Andrzej Strojwas CMU]

- Dynamic (active) corners

- Specify a vast number of process corners (Monte Carlo spread) but figure out which ones really *matter*, either up front, or on the fly

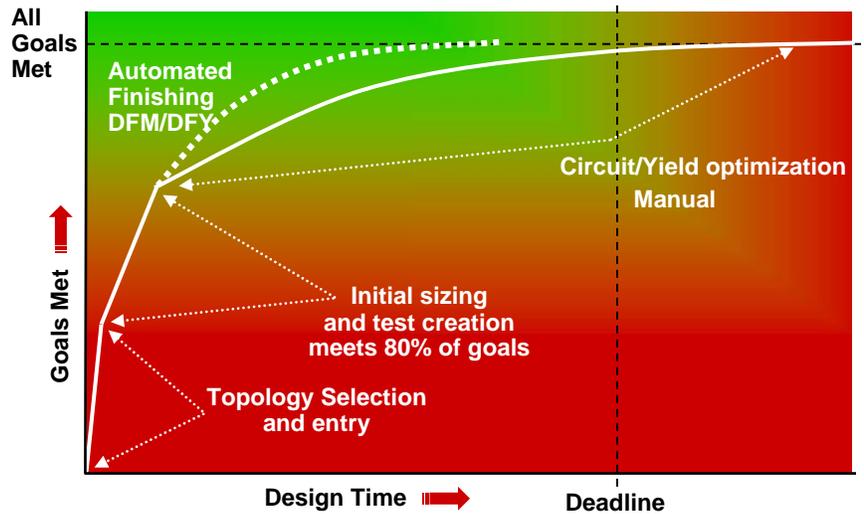


[Mukherjee et al, IEEE TCAD'00]

© R.A. Rutenbar 2006 Slide 34

One Usage Model: *Circuit Finishing*

- DFM/DFY by hand is **painful**: last 20% of design takes 80% of time



[Source: Cadence]

© R.A. Rutenbar 2006 Slide 35

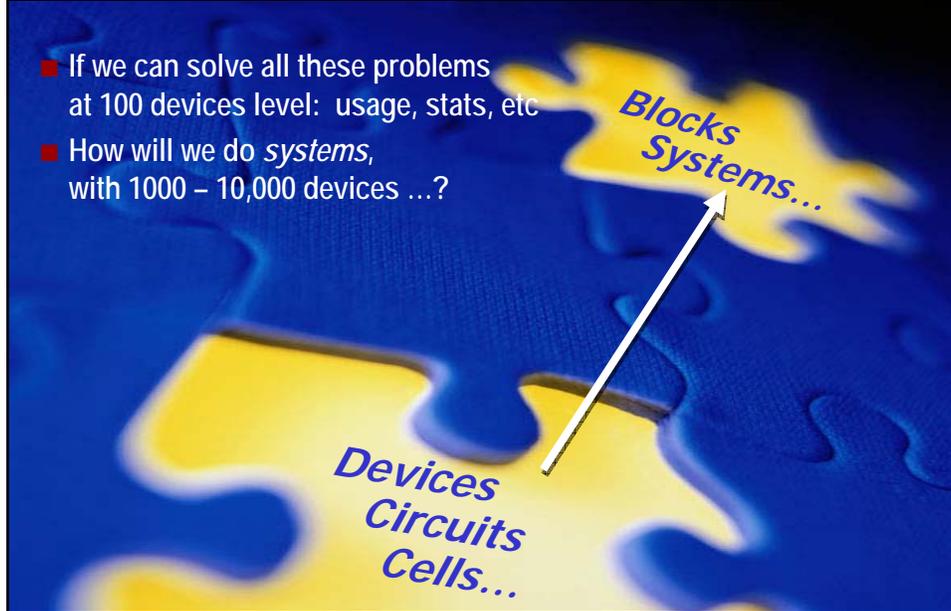
Statistics: Challenges

- **Dimensionality**
 - I don't want to handle just 10 statistical variations, want to handle 10,000
 - Leads to work on statistical dimensionality reduction (principal components)
- **Correlation / complexity**
 - Life would be great if all disturbances were Gaussian & independent.
 - They're not.
- **Optimization**
 - Once got statistics / dimensionality handled, how do formulate optimization?
 - And, optimizing what cost function form? Linear, quadratic, convex, arbitrary?
- Lots of different ideas bubbling around now; *active* area

© R.A. Rutenbar 2006 Slide 36

(3) Scalability: Long-Term Challenge

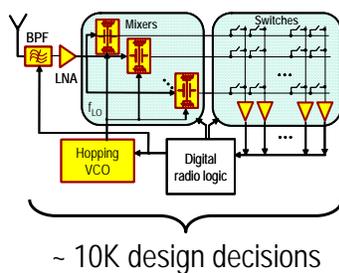
- If we can solve all these problems at 100 devices level: usage, stats, etc
- How will we do *systems*, with 1000 – 10,000 devices ...?



Why Not Synthesize *Flat*, like a Basic Circuit?

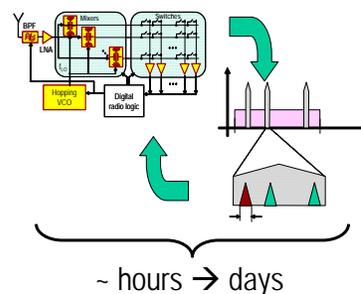
■ Too complex

- Too many design decisions for effective optimization



■ Too slow to evaluate

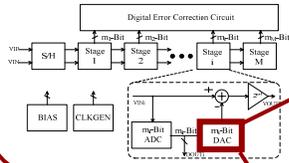
- Simulation-based synthesis needs to simulate *each* candidate solution many times during search



© R.A. Rutenbar 2006 Slide 38

Strategy: Hybrid Optimization

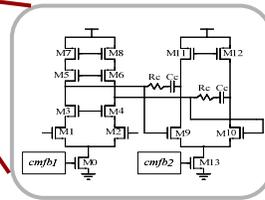
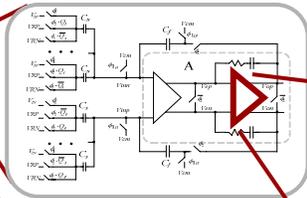
- Idea: Use same infrastrct, *replace* simulators
 - Simulation-based optimization is natural for individual circuits
 - Equations, parameterized by circuit sims, natural for bigger systems



Arbitrary Designer Eqns

$$n_q + \sum_{i=1}^M n_{i, \text{input}} < \frac{(2^{N-1} \Delta)^2 / 2}{10 \frac{\text{SNR}_{\text{max}}}{10}}$$

$$|V_{\text{out}}(t = T1) - V_{\text{slew_ideal}}| \leq V_{\text{tol}}$$



+ Ckt Simulations

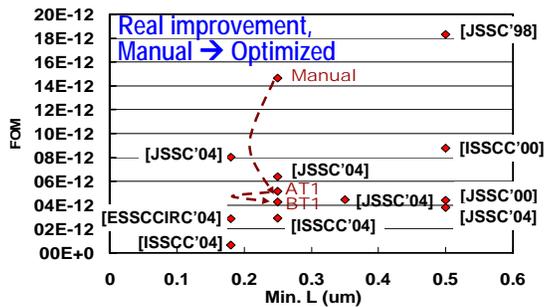
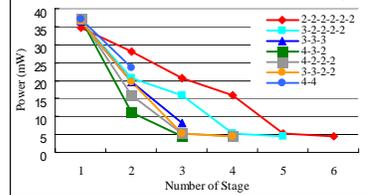
Example: Hybrid Synthesis Solution



- CMU (US) + ITRI (Taiwan) collaborative design
- 40MS/s 13b pipelined ADC
69.2dB SNR @ 250nm
- Equations + sims + optimization

[Chien, Mukherjee et al, ASSCC'05]

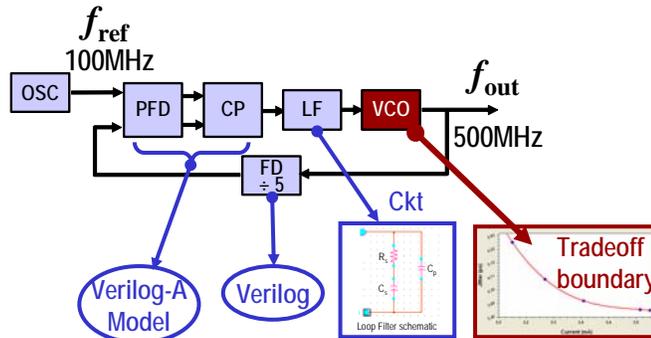
Smart architecture tradeoff analysis



AT1: First two MDAC stages synthesized
BT1: All MDACs synthesized

Another Idea: Replace Circuits with Tradeoff Curves

- Replace device blocks with either simple macromodels or *optimal tradeoff curves* obtained via circuit-level auto-sizing
 - Abstract away device details into essential tradeoffs that matter for system
 - Example: for the VCO in a PLL, Power vs Jitter for a VCO
 - System level "sizing" chooses right points on curve for each block

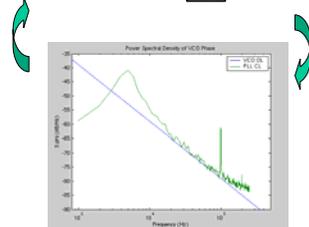
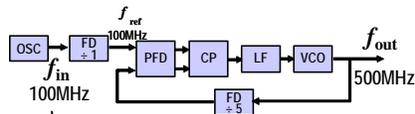


[Tiwary, et al, Proc. Nanotech 2004 Conf.]

© R.A. Rutenbar 2006 Slide 41

Reminder: Why is Sizing the PLL So Hard?

- Why is this hard?
 - 2 hours in SpectreRF to simulate enough cycles to estim PLL jitter
- Consequences
 - Cannot visit enough candidate solutions to find a good final ckt
 - Cannot synthesize this flat
 - Better simulators will help, but they cannot erase this problem



VCO openloop phase noise compared with that in C-L

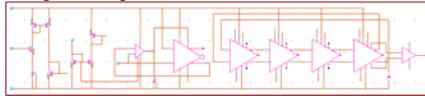
- Solution
 - Need to replace individual ckts with appropriate macromodels
 - Need to reduce number of variables
 - Need to reduce overall eval time

© R.A. Rutenbar 2006 Slide 42

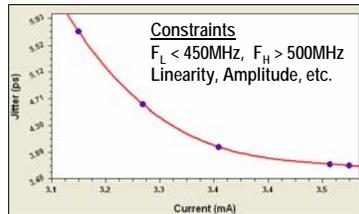
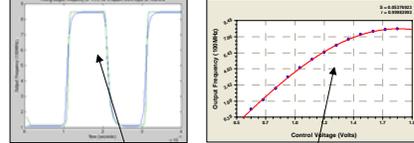
Tradeoff Models: Can Derive with Existing Tools

- Several sizing runs, *carefully* set up, can trace these tradeoff curves

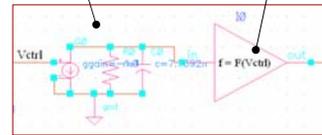
Original ring-oscillator VCO from PLL



One pole for delay Output freq (f) = F(Vctrl)



Bias current vs Jitter tradeoffs

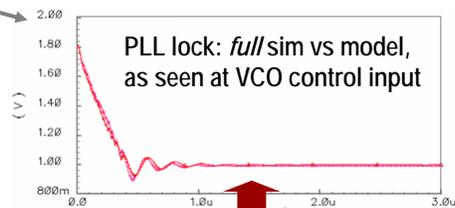
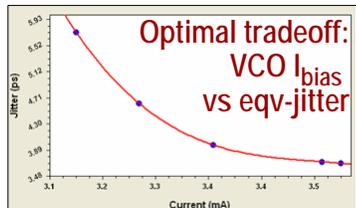
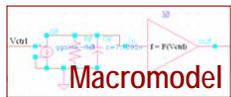
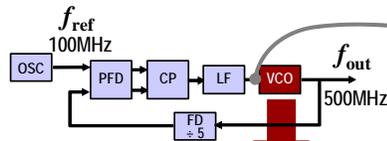


Manually derived model template lets us simulate a VCO for *any* pt on this curve

[Tiwary, et al, Proc. Nanotech 2004 Conf.]

© R.A. Rutenbar 2006 Slide 43

Complete PLL Synthesis Results



PLL lock: *full* sim vs model, as seen at VCO control input

Target PLL simulated 4000 cycles for *each* synthesis pt, ~4hrs on 1 CPU to optimize, for example:

PLL settling time: 0.822 us
 VCO bias current: 3.37 mA
 PLL jitter: 0.46% (9.1ps)



[Tiwary, et al, Proc. Nanotech 2004 Conf.]

© R.A. Rutenbar 2006 Slide 44

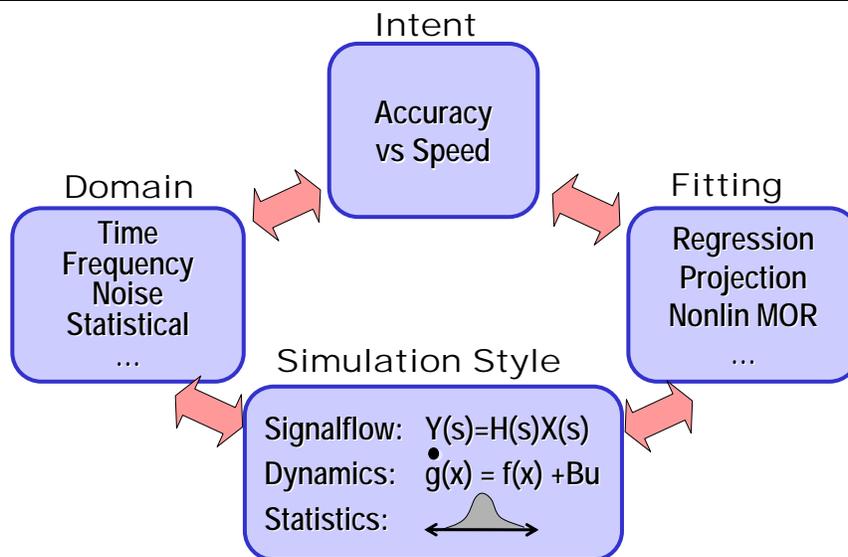
(4) Macromodeling: Long-Term Challenge



"The Allegory of St. Darlington," from Pane 37, North window, Central vault, Notre Linear

© R.A. Rutenbar 2006 Slide 45

Why So Hard? End-Use Diversity Complicates Problem



© R.A. Rutenbar 2006 Slide 46

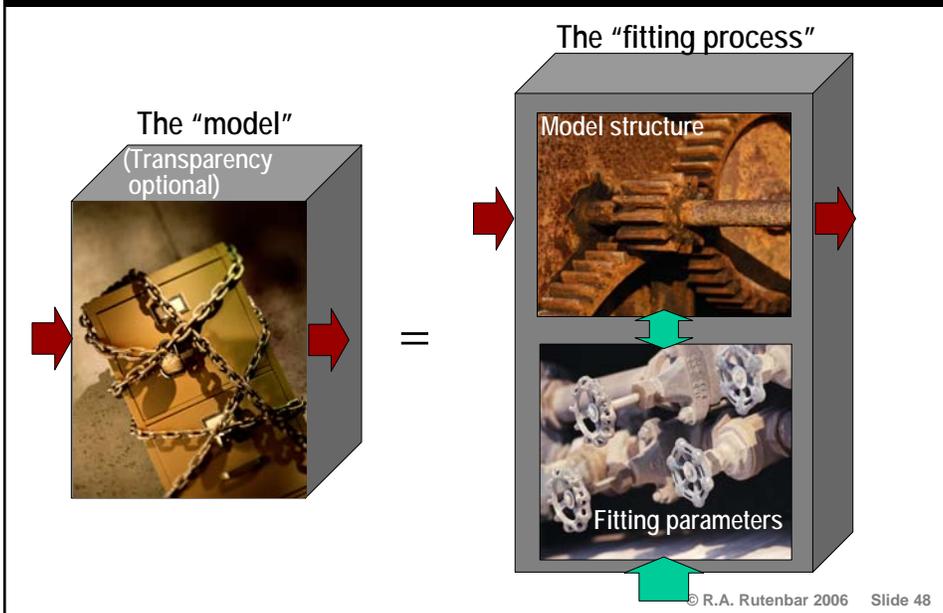
...As Do User Expectations



- Like simulator controls, everybody hates having to “twiddle” model details
- This is what every designer *ultimately* wants

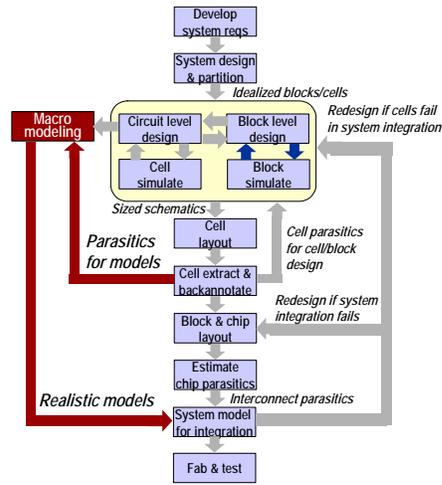
© R.A. Rutenbar 2006 Slide 47

Today's Models Don't Always Inspire Confidence



Why Macromodeling Matters

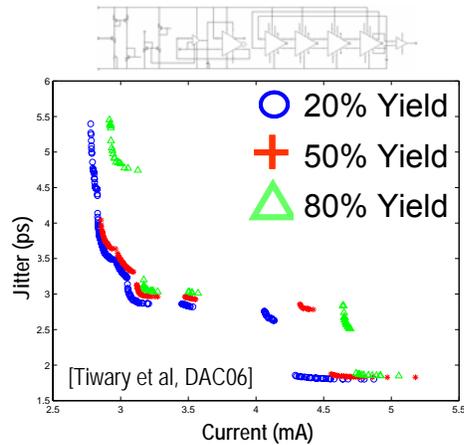
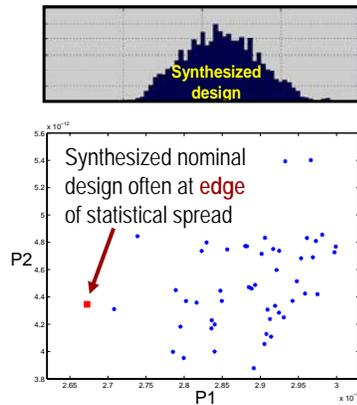
- Rutenbar's Rule:
 - "Everybody who starts out working on optimization, ends up working on macromodeling"
- Why
 - As we get optimization methods that are increasingly *practical*...
 - ...we want more tools to automatically *abstract* circuits
 - ...we expose *weaknesses* in simulation-based verification methodology, for full systems



© R.A. Rutenbar 2006 Slide 49

Lots of Cross-Links Across 4 Challenges

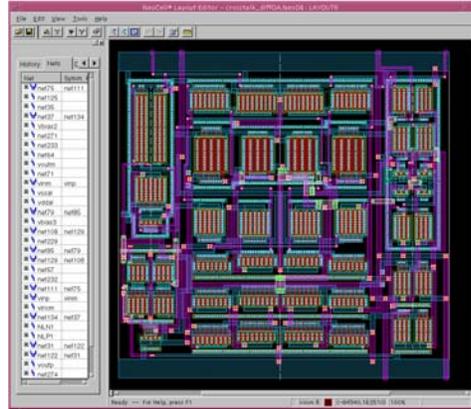
- Statistical... tradeoff macromodels ... for system optimization
- Statistical tradeoff surfaces – tradeoff curves with *yield nums*



© R.A. Rutenbar 2006 Slide 50

Summary

- Analog CAD
 - Not an oxymoron
 - We're making progress
 - Lots of optimization ideas in first gen commercial form
- New challenges
 - Usability
 - Statistics
 - Scalability
 - Macromodeling
- High hopes of analog CAD job security in coming years...

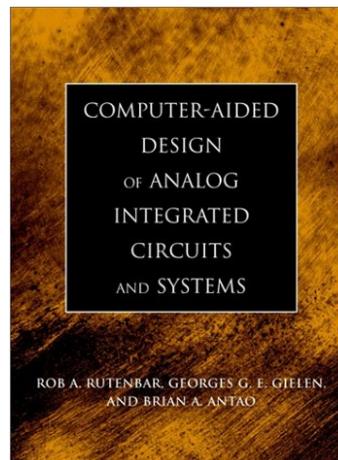


Courtesy Cadence

© R.A. Rutenbar 2006 Slide 51

To Learn More: Mixed-Signal CAD

- Computer-Aided Design of Analog Integrated Circuits and Systems
 - Rob A. Rutenbar, Georges G. E. Gielen, Brian A. Antao, Editors
 - Hardcover: 768 pages
 - Publisher: IEEE
 - Published: April 2002
 - ISBN: 047122782X
- Book is a collection of essential papers on all aspects of analog and mixed signal synthesis, modeling, layout, etc. Most of the results shown here appear in these papers.



© R.A. Rutenbar 2006 Slide 52

Acknowledgements

- Thanks to several people for contributions to this talk
- From CMU
 - Prof. Rick Carley, Prof. Tamal Mukherjee, Pragati Tiwary
- From Cadence
 - Nigel Bleasdale, Dr. Anthony Gadiant, Dr. Hongzhou Liu, Dr. Rodney Phelps, Akshat Shah, Dr. Saurabh Tiwary, Dr. Hodge Worsham
- From ITRI, Taiwan
 - Yu-Tsun Chien, Gin-Kao Ma
- From TI, Dallas
 - Dr. Mike Krasnicki, Jimmy Hellums

© R.A. Rutenbar 2006 Slide 53